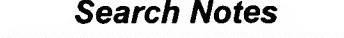


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/998,726	ESTEVEZ, LEONARDO W.
Examiner	Art Unit	
TAN X. DINH	2627	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner